

Possible IJCLab's contribution to the R&D for the Einstein Telescope Vacuum



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September 30, 2022





Outline

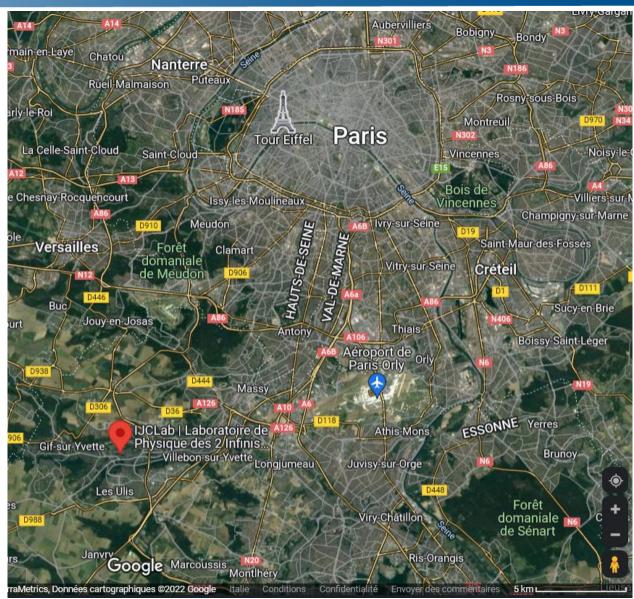
- Presentation of IJCLab
- > Instrumental platforms of interest at IJCLab
- Proposal for IJCLab contribution for vacuum studies in ET tower
- Conclusion and perspectives



IJCLab = Laboratoire de Physique des deux infinis Irene Joliot Curie

30 km South of Paris in the campus of the Paris-Saclay University







IJCLAB https://www.ijclab.in2p3.fr/en/ijclab-2/overview/

• In 2020: a merger of 5 laboratories of ORSAY valley (LAL, IPNO, CSNSM, LPT, IMNC)

- 7 scientific poles:
 - Nuclear Physics
 - High-Energy Physics
 - Astroparticles, astrophysics and cosmology
 - Energy and environment
 - Health physics
 - Theoretical physics
 - Accelerator Physics :
 - ALEA: Laser-plasma acceleration
 - BIMP : Beam Dynamic & diagnostics
 - MAVERICS : Materials Science, Vacuum & SRF
 - > Vacuum & Surface Plateforms : Materials Characterization and UHV studies
 - RF Technology service
 - > Cryogenics service: Design and operation of cryogenic systems for accelerators

ONDES GRAVITATIONNELLES

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740 Collaborators

220
Researchers & Technicians
370

Administrative Support services

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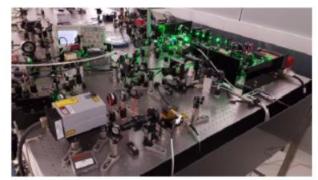
Some instrumental platforms of interest at IJCLab



CALVA: dedicated platform for GW detectors

- First developed to test new technics to acquire control of suspended cavities for GW interferometers
 - Laser injection in in-vacuum 50m long cavity with suspended mirrors
 - Virgo electronics and software to ease integration
 - Control strategy development
- Test now new optical design for squeezing technic in common with LKB, LMA, LAPP – 2 ANRs (Exsqueez/Qfilter)
 - Frequency dependent squeezing allow to beat the standard quantum limit observed in GW detectors
 - Need knowledge on non linear optics (LKB), low loss optics (LMA), low noise electronics (LAPP) and low noise control of cavities (IJCLab)
 - Prepare in-vacuum system study also possible implementation in Advanced Virgo
 - Test possible schemes for 3rd generation of GW detectors
 - Test low noise wavefront corrections
- Host 2 PhDs, 20+ internships (L2 to M2) in the last 10 years

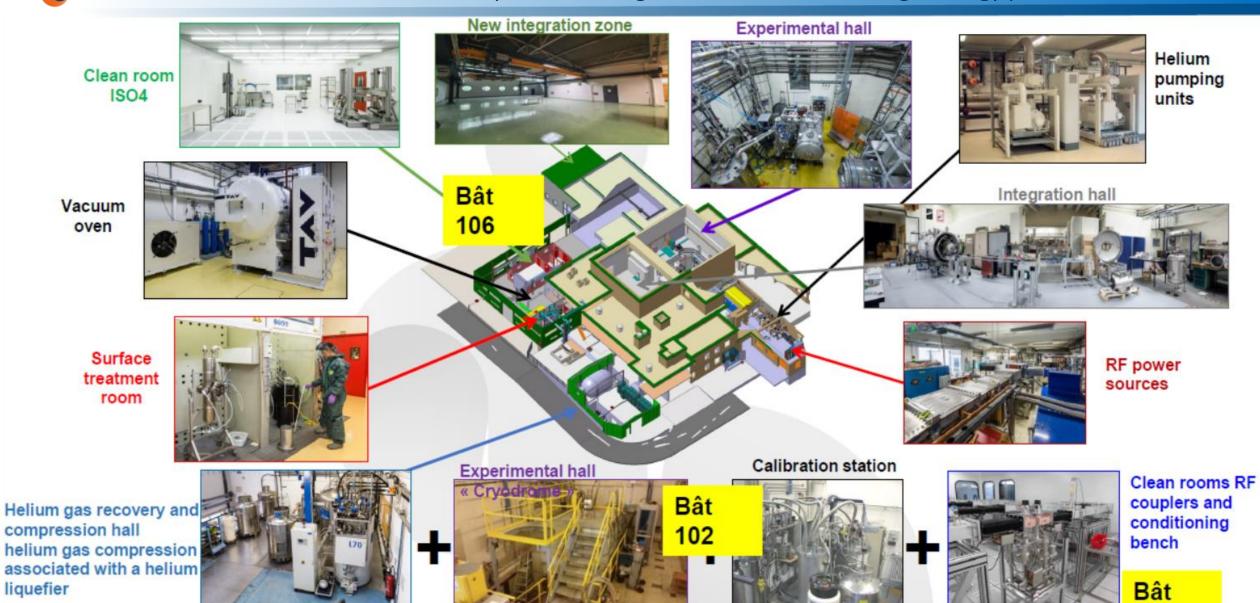
Driven by the GW team





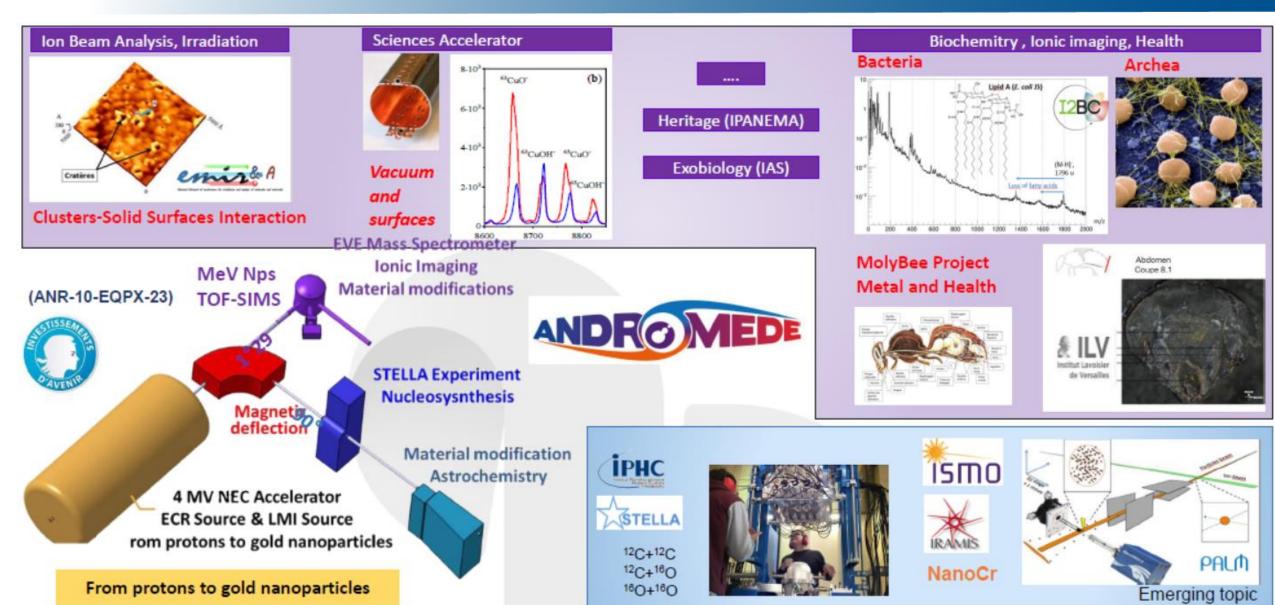


SUPRATECH: dedicated to R&D on Superconducting RF Cavities for future high energy particle accelerators





ANDROMEDE platform: a facility dedicated to interdisciplinary research

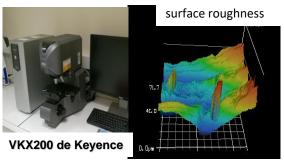




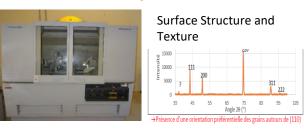
Vacuum&Surfaces platform

Dedicated to characterization and surface analysis of materials used in accelerator technology + UHV studies

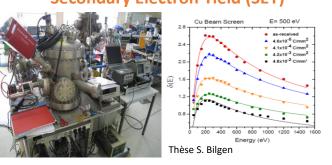
Confocal Microscope



X-ray diffractometer



Secondary Electron Yield (SEY)

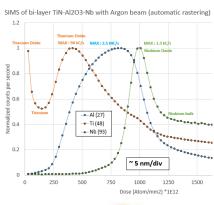


outgassing rate **NEG** coating chamber (Ti,Zr,V)

Secondary Ion Mass Spectrometry (SIMS)



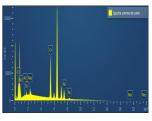
Compact SIMS Hiden Analytical



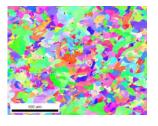
Profile of bi-layer TiN/Al2O3/Nb Thèse S. Birra



Composition (EDS)



Structural (EBSD)



Heat treatment (H2)



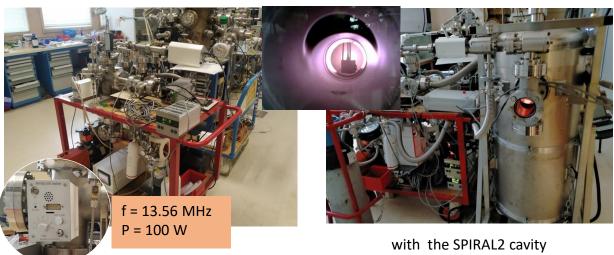
molecular desorption energy



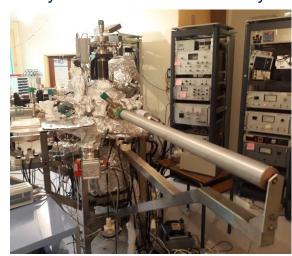


Vacuum&Surfaces platform: new equipment

Plasma cleaning set-up



> Recovery of a multi-technical analysis set-up (ISIS from ICMMO)



2022

SEY

XPS

LEED

RGA

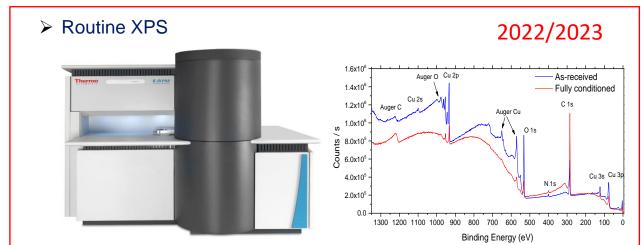
ion gun

@ RT / 1000 K

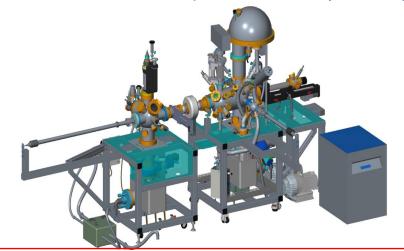
Funding: EQUIPEX+ PACIFICS







➤ Multi technical set-up — Surface analysis at cryogenic temperature



SEY XPS RGA ion gun

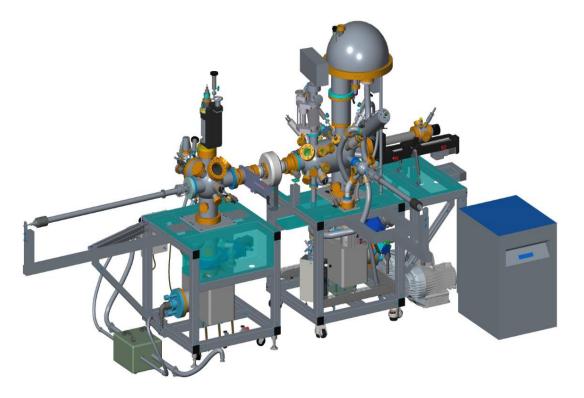
@ 10K



New multitechnical set-up — Surfaces analysis at cryogenic temperature

Dedicated to the analysis of materials for accelerators: SEY measurements coupled with XPS analysis at 10K (e- gun, ion gun, RGA...)

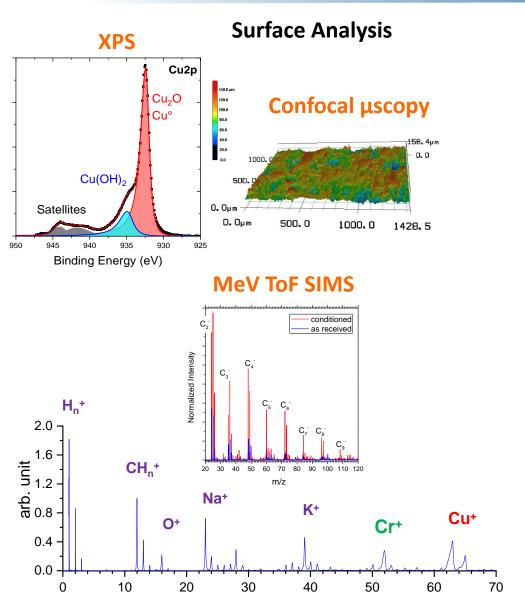
It could be used to investigate some issues related to GW mirrors (charging effets, cleaning processes...)



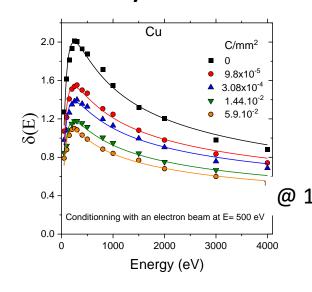
Specification, design under discussion



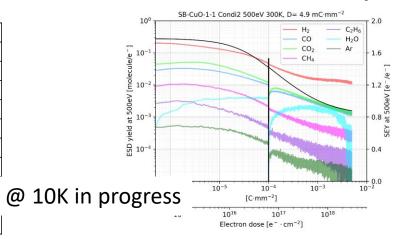
Possibility for benchmark analysis



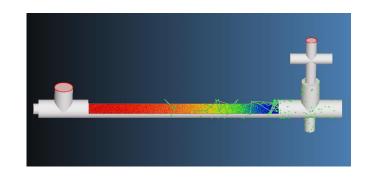
Secondary Electron Yield



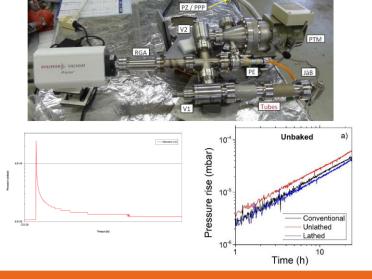
Electron Stimulated Desorption



Molflow calculation



Outgassing rate





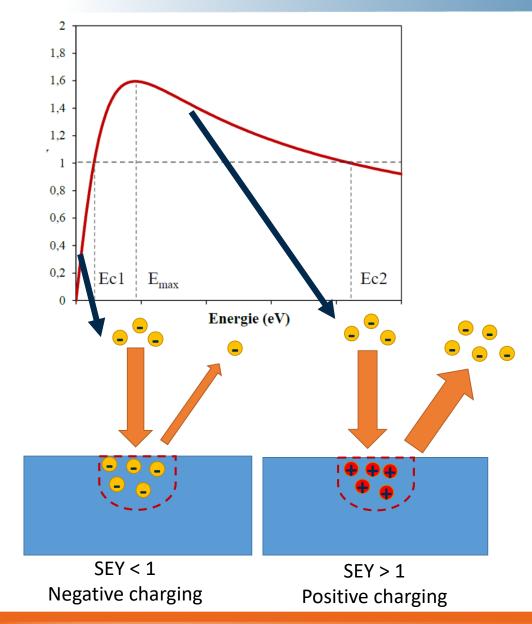
Proposal for IJCLab contribution for vacuum studies in ET tower

- Charging effects in insulators (mirrors)
- > Frosting on mirrors / Contamination of mirrors : new cleaning processes

These issues also represent interesting topics in the field of materials for accelerators (similar centre of interest)



Benchmark analysis: charging effect in insulators



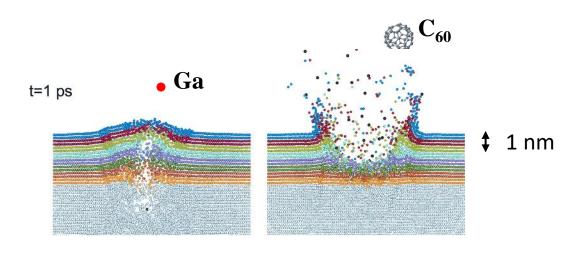
Neutralization of electrostatic charge on mirrors in GW detectors

- Electron gun (flood gun) to irradiate the surface with low energy electrons (pay attention to C contamination coming from the filament of the e- gun: by using new e- gun based on ECR source*?)
- UV photon irradiation (for polymers)
- Perhaps positive ion beams/cluster ion beams to neutralize negative charging
- Tools at IJCLab will be available to investigate the charging effect in insulators @10 K with the new set up

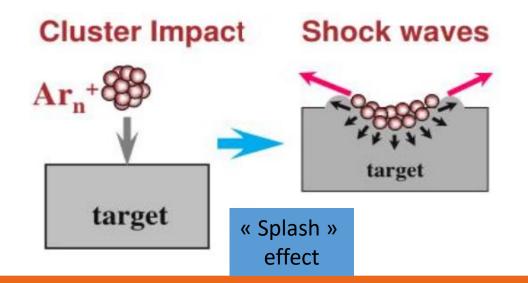
*electron cyclotron resonance

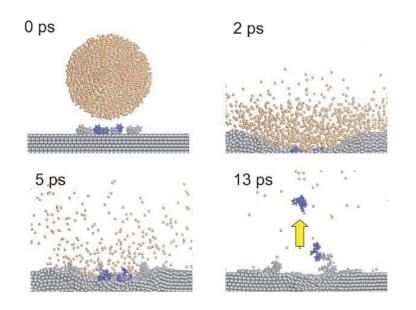


Using the Cluster ion beam cleaning: mirrors cleaning/ice removing?



Postawa Z. et al. J. Phys. Chem. B **2004**, 108,7831-7838 Garrison B. J. & Postawa Z. Mass Spectrom. Rev **2008**, 27, 289-315



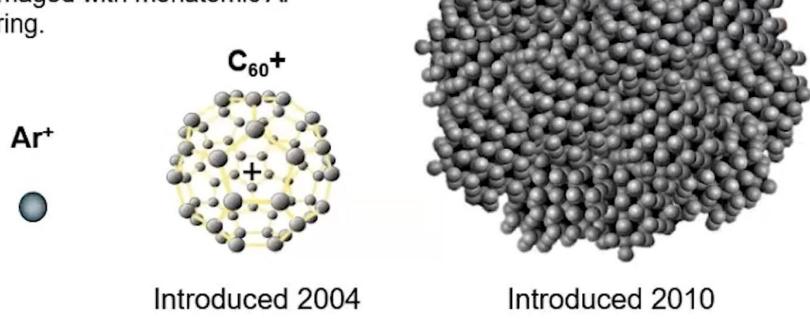


- •Gas Cluster Ion Beams (GCIB) impact a surface with very low energy, down to as little as 1 eV per atom.
- •At such low energies they sputter material without modifying the surface chemistry, i.e. without breaking bonds
- Cleaning effect without materials damage (unlike single ions)
- > Sputtering of organic layers without destroying the underlying layers (only the extreme surface is impacted)



Cluster ion cleaning: for ice removing?

Cluster ion beam sputtering provides access to quantitative chemical state information below the surface for many organic and polymer materials that would typically be damaged with monatomic Ar ion gun sputtering.



Ar₂₅₀₀+

Cluster beam of Ar_n (1<n<3000): Surface cleaning without contamination



An example of cluster ion beam gun

Ion Gun Options on PHI VersaProbe Systems

Standard monatomic Ar ion gun

- 5 V to 5 kV
- Floating column provides high current / low voltage ion beams
- Provides low-energy ions for dual-beam charge neutralization

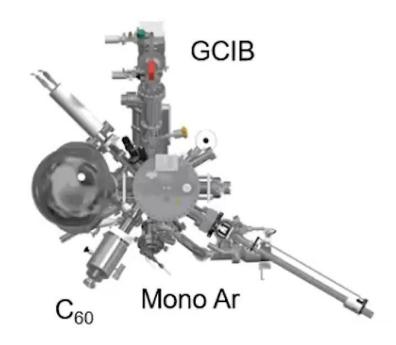
Optional C₆₀ ion gun

- Beam voltage 10 to 20 kV
- Mass filtered ion beam

Optional argon cluster ion gun (GCIB)

- Tunable cluster size up to ~2500 argon atoms
- Beam voltage 2.5 to 20 kV
- Mass filtered ion beam

Cluster size measurement tool now available





An other example of cluster ion gun



GCIB 10S

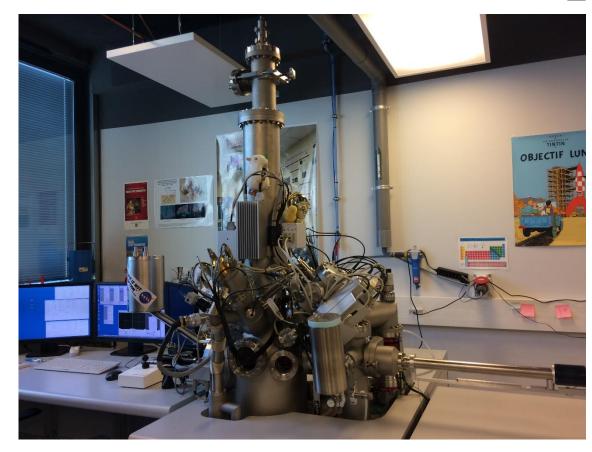
IONOPTIKA

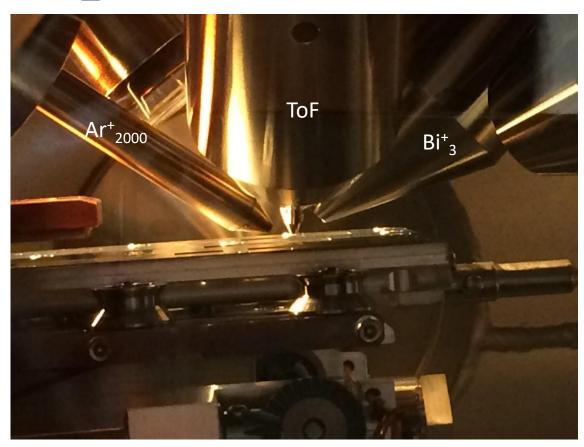
- •10 keV argon cluster ion source
- •Selectable clusters from Ar1 to > Ar3000



An example of application of cluster ion beam cleaning before surface analysis: test for Cu

ToF SIMS_IonToF_Jussieu





Conditions of analysis: 10 keV, beam diameter= 2-4 μm

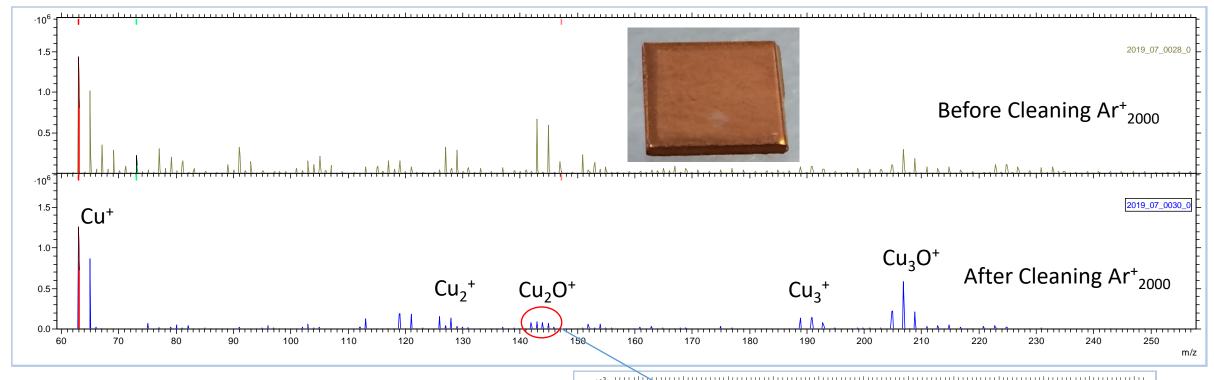
 Bi_{3}^{+} : 250 x 250 μm^{2} , 50 scans, 128 x 128 pixel², dose : 3,8.10¹¹ ions/cm²

 Ar^{+}_{2000} : 1000 x 1000 μm^{2} , 20 s, dose : 9,7.10¹³ ions/cm²

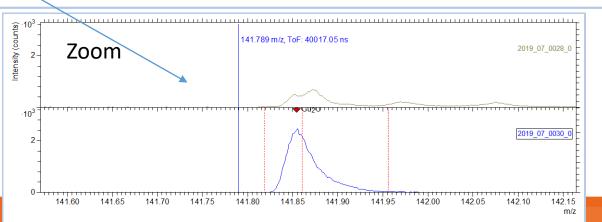


Application of cluster ion beam cleaning for Secondary Ion Mass Spectrometry – ToF SIMS

Mass Spectra: Positive ions

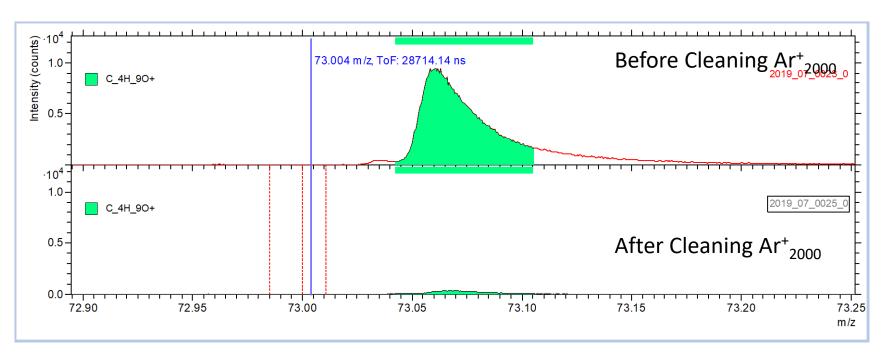


- Contaminants and organic compounds are removed from the surface
 - Cu signal is higher because the contaminant layer was removed



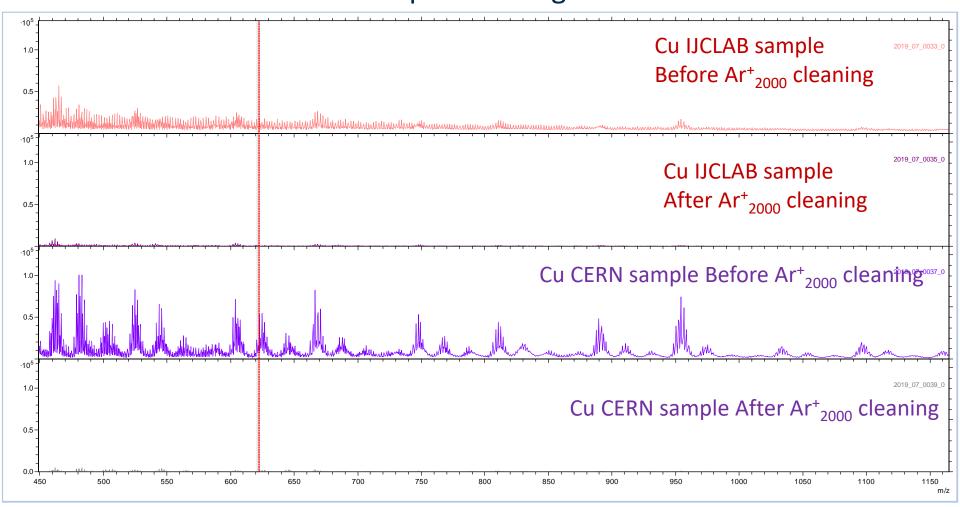
Application of cluster ion beam cleaning for Secondary Ion Mass Spectrometry – ToF SIMS

—[O-Si(CH3)2]n—
PDMS (Polydimethylsiloxane)
silicone polymer family



Application of cluster ion beam cleaning for Secondary Ion Mass Spectrometry – ToF SIMS

Mass spectra: Negative ions



High efficiency to remove contaminants



Conclusion and perspectives

IJCLab contribution to the R&D of the ET Tower vacuum

- > Issues concerning mirrors:
 - (i) Neutralization of the Electrostatic charge forming on mirrors (benchmark analysis with other Research teams)
 - (ii) Surface cleaning/ice removing by cluster ion beam cleaning
 - > expertise in the lab for using cluster ion beams to clean surfaces (ANDROMEDE platform)
 - > it is necessary to perform experiments to test the efficiency of this process on materials of interest
 - complementary to other mitigation strategies (UV photons, low energy electrons...)
- > Perspectives R&D:

Design a multitechnic set up to fit this kind of investigation (we have the funding...)

IJCLAB









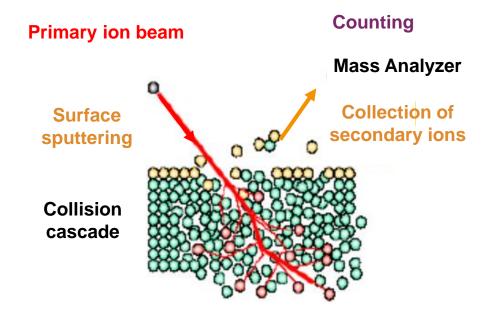
Thanks for your attention

SIMS: Principle













12MeV – Au₄₀₀⁴⁺ nanoparticle beam

- LMIS source
- ❖ Pulsed beam = gold nanoparticles
- Intensity= 3 MeV/q = 12 MeV
- ❖ Size = 100 µm diameter
- **❖** Current <10 pA
- ❖ Line for analysis at 1°29 with 2 collimators to adjust the position at 100 nm precision





Sample

12MeV – Au₄₀₀⁴⁺ nanoparticle beam

- ✓ Large multiplicity (10 to 1000 ions detected per impact).
- ✓ Large efficiency detection.
- ✓ It is possible to obtain a Time Of Flight Secondary Ion Mass Spectrum with only one impact.





Sample

12MeV – Au₄₀₀⁴⁺ nanoparticle beam

- ✓ Large multiplicity. Huge intensity of the signal
- ✓ Large efficiency detection.
- ✓ It is possible to obtain a Time Of Flight Secondary Ion Mass Spectrum with only one impact. ———— Quasi non-destructive analysis